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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/173,048	06/18/2002	Richard J. Evans	1875.1590001	4162
26111	7590	09/28/2005	EXAMINER	
STERNE, KESSLER, GOLDSTEIN & FOX PLLC 1100 NEW YORK AVENUE, N.W. WASHINGTON, DC 20005			CHUNG, PHUNG M	
			ART UNIT	PAPER NUMBER
			2133	
DATE MAILED: 09/28/2005				

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Serial No. : 10173048
Applicant : Richard J. Evans
Filing Date : June 18, 2002
Date Mailed : September 28, 2005

ACKNOWLEDGEMENT OF REQUEST

Notice of Allowance/Allowability Mailed

The request for a copy of the initialed PTO 1449, dated September 12, 2005, has been received by the U.S. Patent and Trademark Office.

- Requested copy attached

D. Perkins
For the Office of Patent Publication

AUG 22 2002

FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT

ATTY. DOCKET NO.
1873.1590001

APPLICATION NO.
10/173,048

APPLICANT
Richard J. EVANS

FILING DATE
June 18, 2002

GROUP ~~2482~~ 2133

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
<i>one</i>	AA1	5,640,509	05/1997	Belmer et al.			
	AB1	5,740,412	04/1998	Chan et al.			
	AC1	5,987,635	11/1999	Kishi et al.			
<i>one</i>	AD1	6,001,662	12/1999	Correale, Jr. et al.			
	AE1						
	AF1						
	AG1						
	AH1						
	AI1						
	AJ1						
	AK1						

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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
	AL1						Yes No
	AM1						Yes No
	AN1						Yes No
	AO1						Yes No
	AP1						Yes No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

AR	1	Bordell et al., "Bulls-in Test For VLSI: Pseudorandom Techniques", p. 342, John Wiley & Sons, New York, 1987.
AS	1	Dekker et al., "Fault Modeling and Test Algorithm Development for Static Random Access Memories", pp. 343-353, IEEE Int'l Test Conference, 1988.
AT	1	Brauch et al., "Design of Cache Test Hardware on the HP PA8500", pp. 58-63, IEEE Design & Test of Computers, 1998.

EXAMINER

DATE CONSIDERED 10/4/21

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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